

Conference Agenda

Session

SES-09: Material Characterization II

Time: Friday, 07/Feb/2025: 9:00am - 10:20am

Presentations

Sparse-view Material Decomposition for Spectral X-ray CT using Neural Radiance Fields

Takumi Hotta^{1,4}, Tatsuya Yatagawa², Yutaka Ohtake¹, Toru Aoki^{3,5}

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Volumetric sub- μ -CT imaging for forensic wood identification

Jannik Stebani^{1,2}, Tim Lewandrowski³, Kilian Dremel¹, Simon Zabler^{1,4}, Volker Haag³

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Determination of the image quality in computed tomography and its standardisation

Anne-Françoise Obaton¹, Uwe Ewert², Holger Roth³, Janka Wilbig¹, Clément Remacha⁴, Nicolas Cochenec⁴, Lionel Gay⁴, Marko Katic⁵

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Single X-ray Projection Material Decomposition using a Mesh Projector

Fleur Linsen¹, Domenico Iuso^{1,2}, Jan Sijbers^{1,2}

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